

GETTING YOUR OWN  
TECHNICAL AND OPTICAL DESIGN  
DOING IT THE SMART WAY

DESIGN IT YOURSELF  
DOING IT THE SMART WAY

Test (USIM) Product	Prod. No.	Available on stock	Same default values for all cards**	Individual IMSI and Ki values for each card	Creation of new data fields possible	OTA	CPHS	GPRS	Fast I/O	3V/5V	1.8V	Java™ Card	SAT Applet "Proactive Commands"
8K GSM Phase 2 Standard 1	10208001	x	x							x			
8K GSM Phase 2 Standard 2*	10208002			x						x			
8K GSM Phase 2 Standard 3	10208003	x	x		x	x	x			x			
8K GSM Phase 2 Standard 4*	10208004			x	x	x	x			x			
8K GSM Phase 2 Standard 5	10208005	x	x		x					x			
8K GSM Phase 2 Standard 6*	10208006			x	x					x			
16K GSM Phase 2 Standard 1*	10216001		x		x	x	x			x			
16K GSM Phase 2 Standard 2*	10216002			x	x	x	x			x			
8K GSM Phase 2+ Standard 1*	10308001		x			x	x	x		x			
8K GSM Phase 2+ Standard 2*	10308002			x		x	x	x		x			
32K GSM Phase 2+ Standard 1	10332001	x	x		x	x	x	x	x	x			
32K GSM Phase 2+ Standard 2*	10332002			x	x	x	x	x	x	x			
32K/J GSM Phase 2+ 1.8V	10332003	x	x		x	x	x	x	x	x	x	x	
32K/J GSM Phase 2+ with the SAT Test & Demo Applet "Proactive Commands"	10332004		x		x	x			x	x		x	x
32K Test USIM	10432001	x	x		x				x	x			

\* min. order quantity of 500 pieces

\*\* except ICCID

Additional ORGA Test Systems  
product information

- Test Equipment
- Accessories

You will always reach us at:

[www.orga-test.com](http://www.orga-test.com)

Editorial  
Editor: Camilla Piper, ORGA Test Systems  
Design: Claus Bruns, KOMMA Design  
Text: Alison Riddell-Kachur

Customised Test (U)SIMs

We offer customised Test (U)SIMs that allow cards to be manufactured according to your technical specifications as well as exposing your own corporate design. You can have one of our standard cards printed with your corporate artwork. For a customised Test (U)SIM a minimum ordering quantity of 500 pieces is required.

How to do it?

Contact our Product Manager to discuss your ideas. Then we can jointly prepare the appropriate specifications and have your card manufactured and distributed worldwide.

Customising tools

To make customising easier we also offer end-to-end Test SIM editing tools – the perfect solution if you want to make changes yourself. We offer a SIM Editor for GSM Test SIMs and a USIM Editor for 3G Test USIMs.

Technical advice given by

**Daniela Wittkamp**  
Product Manager  
Phone: +49-5251-699 86 62  
Fax: +49-5251-699 86 99  
E-mail: [dwittkamp@orga-test.com](mailto:dwittkamp@orga-test.com)

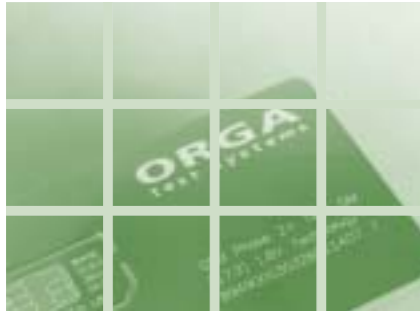
Quotation and order service given by

**Regina Furchner**  
Sales Assistant  
Phone: +49-5251-699 86 66  
Fax: +49-5251-699 86 99  
E-mail: [rfurchner@orga-test.com](mailto:rfurchner@orga-test.com)

TEST (U)SIMs  
TEST (U)SIMs

**ORGA**  
test systems

## TESTING WITH ORGA TEST SYSTEMS – DOING IT THE SMART WAY



### Just in time ordering

We offer a wide range of state-of-the-art standard Test (U)SIMs. Our test cards are also available in smaller quantities – or in bulk depending on your needs.



### Customised? No problem

Once you reach a certain number of test cards, designing your own card might be an interesting option. Our Product Manager would be pleased to help. Why not give us a call?



### Additional tools

We also offer tools to edit our test cards – a SIM Editor for GSM Test SIMs and a USIM Editor for 3G Test USIMs. Of course it goes without saying that we offer a full range of support to help you in selecting and using our tools and systems.



#### 8K GSM Phase 2 Standard 1 Test SIMs

→ Prod. No.: 10208001

- Phase 2 data fields
- 3V / 5V technology
- XOR test algorithm
- 24K ROM, 512 Byte RAM, 8K EEPROM
- PIN 1 disabled

#### 8K GSM Phase 2 Standard 3 Test SIMs

→ Prod. No.: 10208003

- ... plus:
- OTA and CPHS Functionality
- Creation of new data fields allowed

#### 8K GSM Phase 2 Standard 5 Test SIMs

→ Prod. No.: 10208005

- ... plus:
- Alpha tag length of 32 bytes
- Creation of new data fields allowed



#### 32K GSM Phase 2+ Standard 1 Test SIMs

→ Prod. No.: 10332001

- Phase 2+ data fields
- 3V / 5V technology
- XOR test algorithm
- 48K ROM, 3K RAM, 32K EEPROM
- PIN 1 enabled
- OTA, CPHS and GPRS Functionality, Fast I/O
- Creation of new data fields allowed



#### 32K/J GSM Phase 2+ Test SIMs 1.8V

→ Prod. No.: 10332003

- Phase 2+ data fields
- 1.8V / 3V / 5V technology
- Java Card™
- XOR test algorithm
- 136K ROM, 4096 Byte RAM, 32K EEPROM
- PIN 1 disabled
- OTA, CPHS and GPRS Functionality, Fast I/O
- Creation of new data fields allowed



#### 32K/J GSM Phase 2+ Test SIMs with the SAT Test & Demo Applet “Proactive Commands”

→ Prod. No.: 10332004

- Phase 2+ data fields
- 3V / 5V technology
- Java Card™
- XOR test algorithm
- 136K ROM, 4096 Byte RAM, 32K EEPROM
- PIN 1 enabled
- OTA Functionality, Fast I/O
- Creation of new data fields allowed
- SAT Test & Demo Applet
- Encoded icon



#### 32K Test USIM

→ Prod. No.: 10432001

- 3V / 5V technology
- 3G test algorithm
- 64K ROM, 3004 Byte RAM, 32K EEPROM
- PIN 1 disabled
- Creation of new data fields allowed
- Global phonebook
- Fast I/O
- GSM conversion functions to allow 3G terminal access to GSM network

DOING IT THE SMART WAY –  
TESTING WITH ORGA TEST SYSTEMS